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Application/Control No.	Applicant(s)/Patent under Reexamination
10/800,777	FUKUZAWA ET AL.
Examiner	Art Unit
Christopher W. Fulton	2859

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Class	Subclass	Date	Examiner
399	328 329	6/21/2005	CWF
219	216 388	1	]

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Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Ex. Sophia Chen in class 399	6/21/2005	CWF